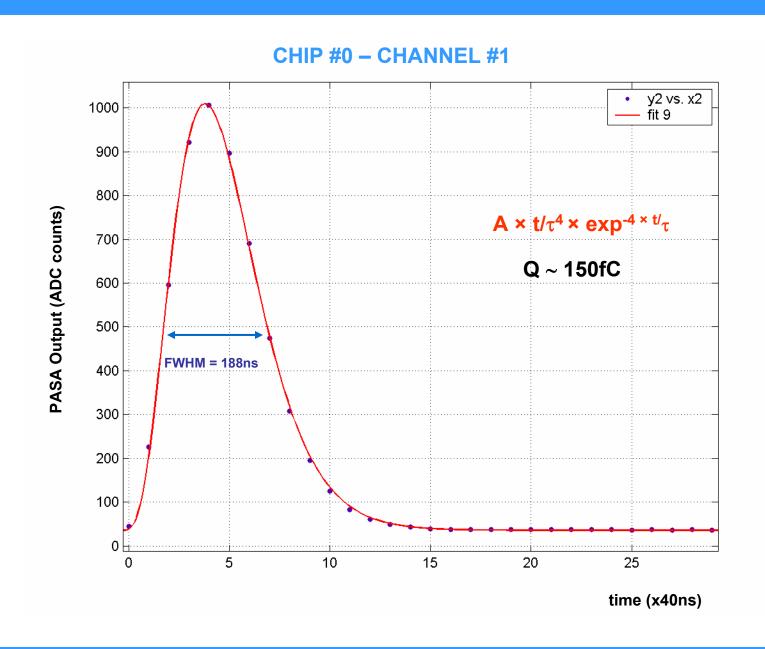
# **Characterization of the PASA Engineering Run Samples**

H.K. Soltveit

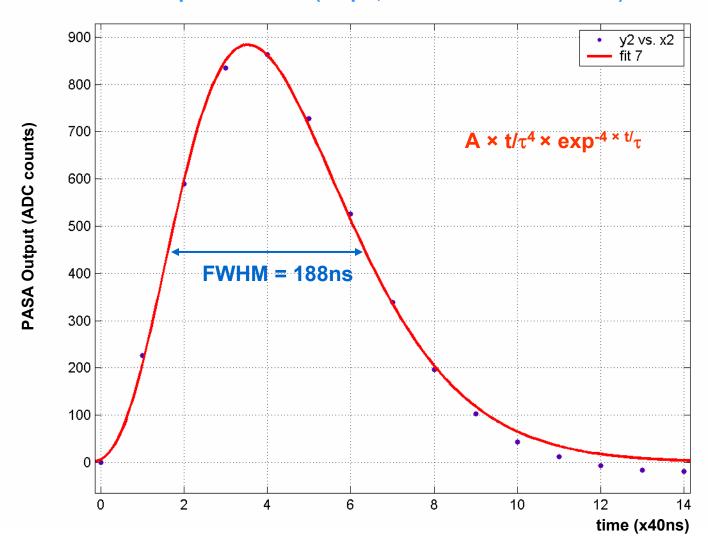
# **Characterization of the PASA ER samples**

- 500 chip packaged in plastic case were delivered 1st week of September
- 16 chips delivered to CERN for the characterization and ER approval
- 2 FEC loaded and ready for test at the TPC Sector test
- 2 chips (32 channels) fully characterized in the laboratory
- The remaining 484 chips delivered to Darmstadt (TU) for screening test (see U. Bonnes presentation)

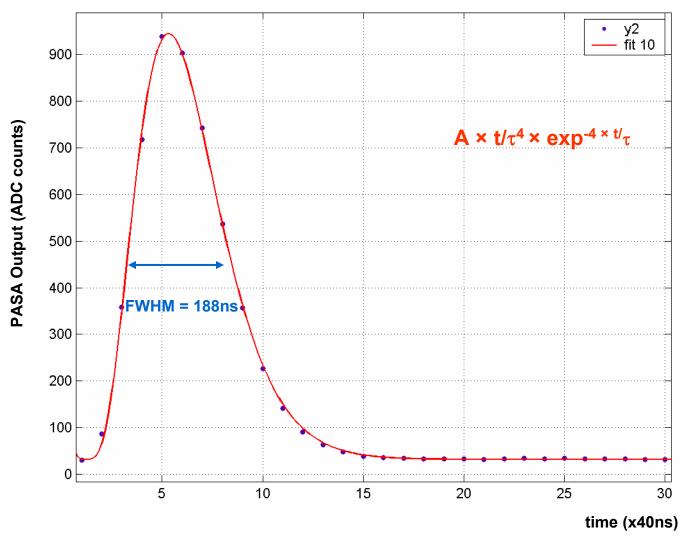


CHIP #1 - CHANNEL #1

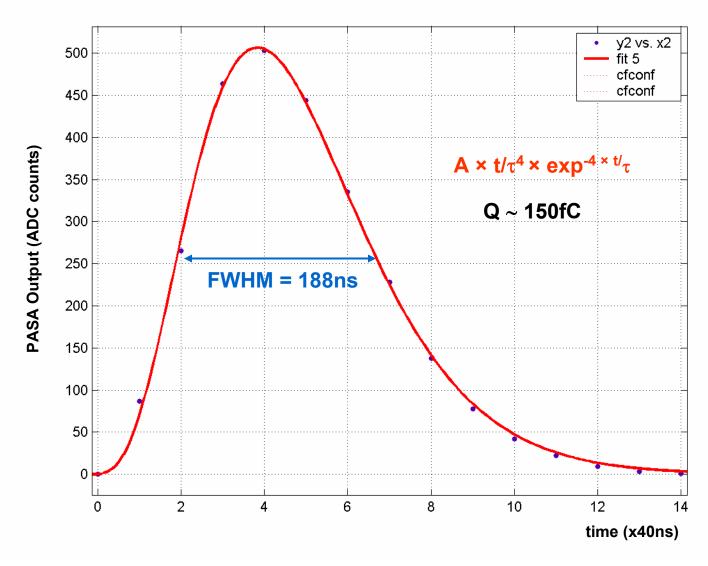
#### extra capacitive load (3.3pF, ~ 45%of nominal value)



CHIP #1 – CHANNEL #1
extra capacitive load (6.6pF, ~ 90%of nominal value)

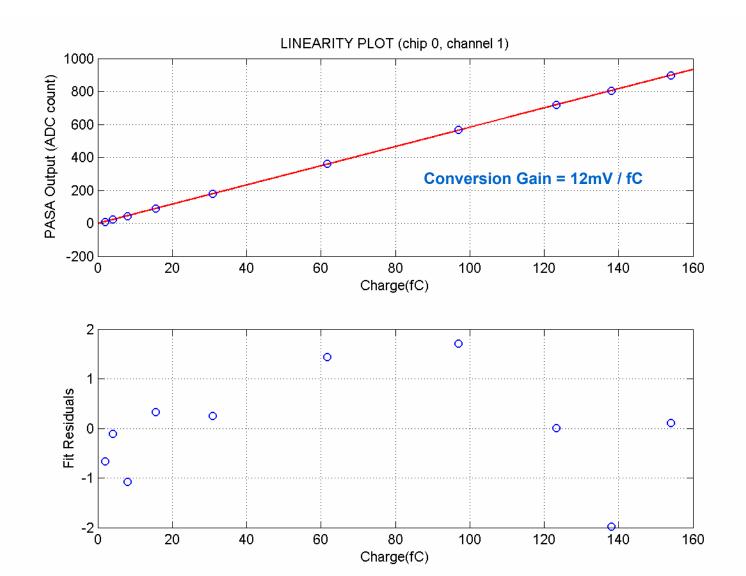






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## **PASA LINEARITY**



# **Summary**

Parameter	Reauirement	MPR Version	ER Version
Noise	1000 e	566 e @12pF	560 e @12pF
Conversion gain	12mV / fC	10.8 mV / fC	12 mV / fC
Shaping time	190ns	190ns	188ns
Non linearity	< 1%	< 0.35%	0.2%
Crosstalk	< 0.3%	< 0.4%	< 0.1%
Baseline's dispersion		200 mV	60 mV
Power consumption	< 20mW / ch	12mW / ch	11mW / ch
Area		16.7mm <sup>2</sup>	18 mm <sup>2</sup>

- > The Engineering Run samples fulfill all requirements
- > Improvements with respect the MPW:
  - crosstalk reduced by at least a factor 4
  - baseline dispersion reduced by a factor 2
  - better design compensation for the inaccuracy of the process models